

100-Pin TQFP
Commercial Temp
Industrial Temp

4Mb Pipelined and Flow Through 180 MHz–100 MHz Synchronous NBT SRAMs

3.3 V V_{DD}
2.5 V and 3.3 V V_{DDQ}

Features

- 256K x 18 and 128K x 36 configurations
- User-configurable Pipelined and Flow Through mode
- NBT (No Bus Turn Around) functionality allows zero wait
- Fully pin-compatible with both pipelined and flow through NtRAM™, NoBL™ and ZBT™ SRAMs
- IEEE 1149.1 JTAG-compatible Boundary Scan
- 3.3 V +10%/–5% core power supply
- 2.5 V or 3.3 V I/O supply
- \overline{LBO} pin for Linear or Interleave Burst mode
- Byte write operation (9-bit Bytes)
- 3 chip enable signals for easy depth expansion
- Clock Control, registered, address, data, and control
- ZZ Pin for automatic power-down
- JEDEC-standard 100-lead TQFP package

		–180	–166	–150	–100
Pipeline 3-1-1-1	tCycle	5.5 ns	6.0 ns	6.6 ns	10 ns
	tKQ	3.2 ns	3.5 ns	3.8 ns	4.5 ns
	I _{DD}	335 mA	310 mA	280 mA	190 mA
Flow Through 2-1-1-1	tKQ	8 ns	8.5 ns	10 ns	12 ns
	tCycle	9.1 ns	10 ns	12 ns	15 ns
	I _{DD}	210 mA	190 mA	165 mA	135 mA

Functional Description

The GS841Z18/36AT is an 4Mbit Synchronous Static SRAM. GSI's NBT SRAMs, like ZBT, NtRAM, NoBL or other pipelined read/double late write or flow through read/single late write SRAMs, allow utilization of all available bus

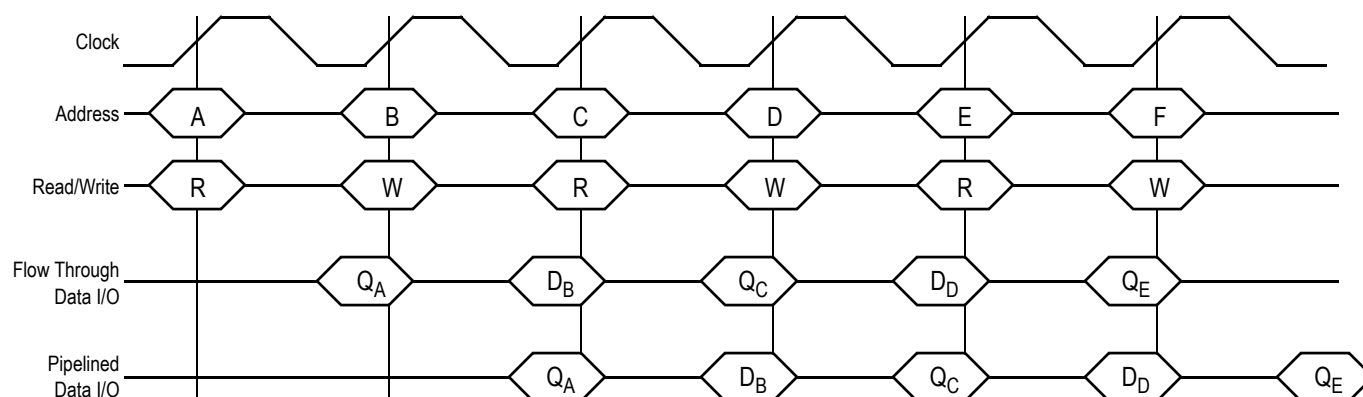
bandwidth by eliminating the need to insert deselect cycles when the device is switched from read to write cycles.

Because it is a synchronous device, address, data inputs, and read/ write control inputs are captured on the rising edge of the input clock. Burst order control (\overline{LBO}) must be tied to a power rail for proper operation. Asynchronous inputs include the Sleep mode enable (\overline{ZZ}) and Output Enable. Output Enable can be used to override the synchronous control of the output drivers and turn the RAM's output drivers off at any time. Write cycles are internally self-timed and initiated by the rising edge of the clock input. This feature eliminates complex off-chip write pulse generation required by asynchronous SRAMs and simplifies input signal timing.

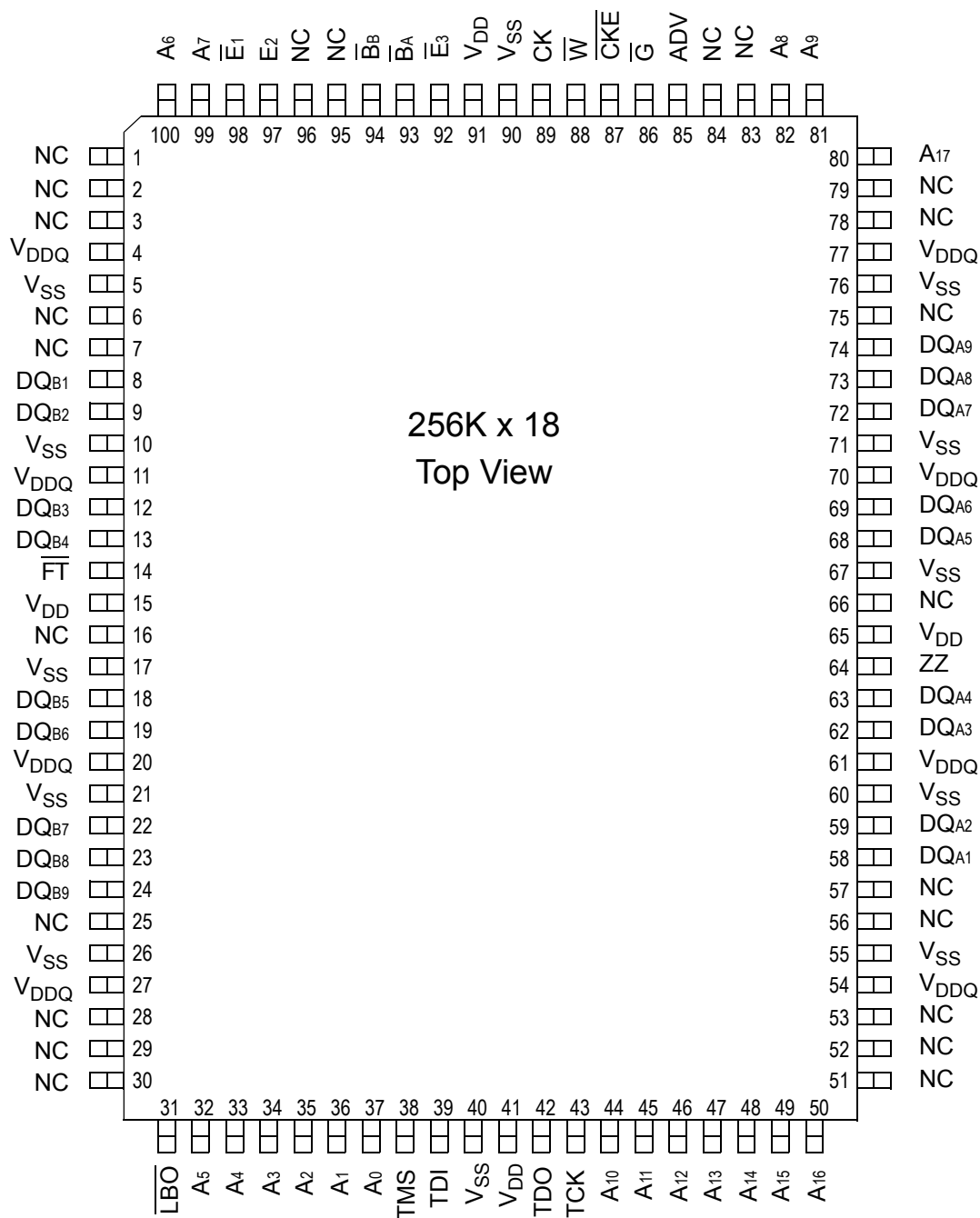
The GS841Z18/36AT may be configured by the user to operate in Pipeline or Flow Through mode. Operating as a pipelined synchronous device, in addition to the rising-edge-triggered registers that capture input signals, the device incorporates a rising-edge-triggered output register. For read cycles, pipelined SRAM output data is temporarily stored by the edge-triggered output register during the access cycle and then released to the output drivers at the next rising edge of clock.

The GS841Z18/36AT is implemented with GSI's high performance CMOS technology and is available in a JEDEC-Standard 100-pin TQFP package.

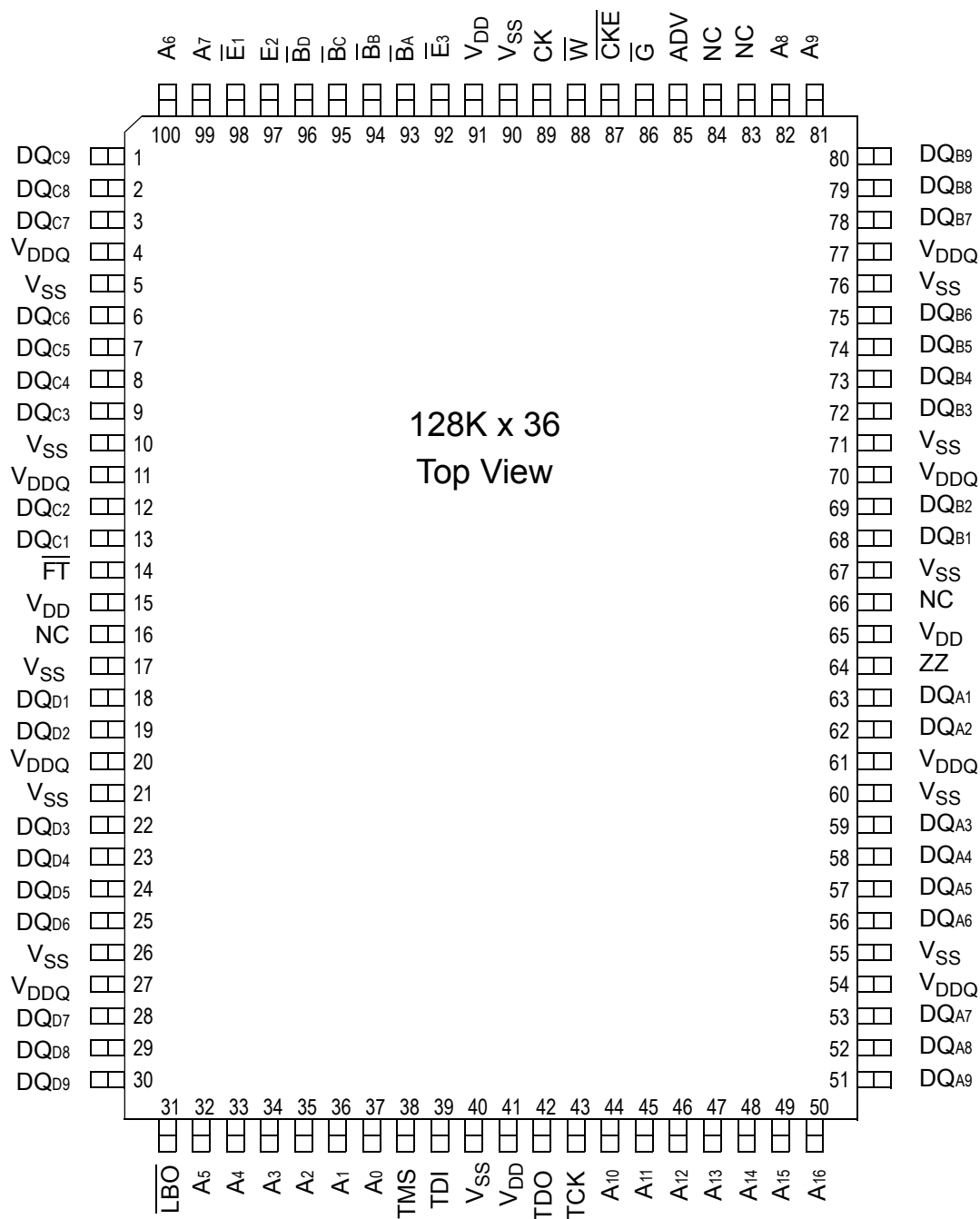
Flow Through and Pipelined NBT SRAM Back-to-Back Read/Write Cycles



GS841Z18AT Pinout



GS841Z36AT Pinout



100-Pin TQFP Pin Descriptions

Symbol	Type	Description
A ₀ , A ₁	In	Burst Address Inputs—Preload the burst counter
A ₂ –A ₁₆	In	Address Inputs
A ₁₇	In	Address Input
CK	In	Clock Input Signal
$\overline{\text{BA}}$	In	Byte Write signal for data inputs DQ _{A1} –DQ _{A9} ; active low
$\overline{\text{BB}}$	In	Byte Write signal for data inputs DQ _{B1} –DQ _{B9} ; active low
$\overline{\text{BC}}$	In	Byte Write signal for data inputs DQ _{C1} –DQ _{C9} ; active low
$\overline{\text{BD}}$	In	Byte Write signal for data inputs DQ _{D1} –DQ _{D9} ; active low
$\overline{\text{W}}$	In	Write Enable; active low
$\overline{\text{E}}_1$	In	Chip Enable; active low
E ₂	In	Chip Enable; active high; for self decoded depth expansion
$\overline{\text{E}}_3$	In	Chip Enable; active low; for self decoded depth expansion
$\overline{\text{G}}$	In	Output Enable; active low
ADV	In	Advance / $\overline{\text{Load}}$ —Burst address counter control pin
$\overline{\text{CKE}}$	In	Clock Input Buffer Enable; active low
NC	—	No Connect
DQ _{A1} –DQ _{A9}	I/O	Byte A Data Input and Output pins
DQ _{B1} –DQ _{B9}	I/O	Byte B Data Input and Output pins
DQ _{C1} –DQ _{C9}	I/O	Byte C Data Input and Output pins
DQ _{D1} –DQ _{D9}	I/O	Byte D Data Input and Output pins
ZZ	In	Power down control; active high
$\overline{\text{FT}}$	In	Pipeline/Flow Through Mode Control; active low
$\overline{\text{LBO}}$	In	Linear Burst Order; active low
TMS	—	Scan Test Mode Select
TDI	—	Scan Test Data In
TDO	—	Scan Test Data Out
TCK	—	Scan Test Clock
V _{DD}	In	3.3 V power supply
V _{SS}	In	Ground
V _{DDQ}	In	3.3 V output power supply for noise reduction
NC	—	No Connect

Functional Details

Clocking

Deassertion of the Clock Enable ($\overline{\text{CKE}}$) input blocks the Clock input from reaching the RAM's internal circuits. It may be used to suspend RAM operations. Failure to observe Clock Enable set-up or hold requirements will result in erratic operation.

Pipeline Mode Read and Write Operations

All inputs (with the exception of Output Enable, Linear Burst Order and Sleep) are synchronized to rising clock edges. Single cycle read and write operations must be initiated with the Advance/ $\overline{\text{Load}}$ pin (ADV) held low, in order to load the new address. Device activation is accomplished by asserting all three of the Chip Enable inputs ($\overline{\text{E1}}$, E2, and $\overline{\text{E3}}$). Deassertion of any one of the Enable inputs will deactivate the device.

Function	$\overline{\text{W}}$	$\overline{\text{BA}}$	$\overline{\text{BB}}$	$\overline{\text{BC}}$	$\overline{\text{BD}}$
Read	H	X	X	X	X
Write Byte "a"	L	L	H	H	H
Write Byte "b"	L	H	L	H	H
Write Byte "c"	L	H	H	L	H
Write Byte "d"	L	H	H	H	L
Write all Bytes	L	L	L	L	L
Write Abort/NOP	L	H	H	H	H

Read operation is initiated when the following conditions are satisfied at the rising edge of clock: $\overline{\text{CKE}}$ is asserted Low, all three chip enables ($\overline{\text{E1}}$, E2, and $\overline{\text{E3}}$) are active, the write enable input signals $\overline{\text{W}}$ is deasserted high, and ADV is asserted low. The address presented to the address inputs is latched in to address register and presented to the memory core and control logic. The control logic determines that a read access is in progress and allows the requested data to propagate to the input of the output register. At the next rising edge of clock the read data is allowed to propagate through the output register and onto the Output pins.

Write operation occurs when the RAM is selected, CKE is active and the Write input is sampled low at the rising edge of clock. The Byte Write Enable inputs ($\overline{\text{BA}}$, $\overline{\text{BB}}$, $\overline{\text{BC}}$, and $\overline{\text{BD}}$) determine which bytes will be written. All or none may be activated. A Write Cycle with no Byte Write inputs active is a no-op cycle. The pipelined NBT SRAM provides double late write functionality, matching the write command versus data pipeline length (2 cycles) to the read command versus data pipeline length (2 cycles). At the first rising edge of clock, Enable, Write, Byte Write(s), and Address are registered. The Data In associated with that address is required at the third rising edge of clock.

Flow Through Mode Read and Write Operations

Operation of the RAM in Flow Through mode is very similar to operations in Pipeline mode. Activation of a Read Cycle and the use of the Burst Address Counter is identical. In Flow Through mode the device may begin driving out new data immediately after new address are clocked into the RAM, rather than holding new data until the following (second) clock edge. Therefore, in Flow Through mode the read pipeline is one cycle shorter than in Pipeline mode.

Write operations are initiated in the same way as well, but differ in that the write pipeline is one cycle shorter, preserving the ability to turn the bus from reads to writes without inserting any dead cycles. While the pipelined NBT RAMs implement a double late write protocol, in Flow Through mode a single late write protocol mode is observed. Therefore, in Flow Through mode, address and control are registered on the first rising edge of clock and data in is required at the data input pins at the second rising edge of clock.

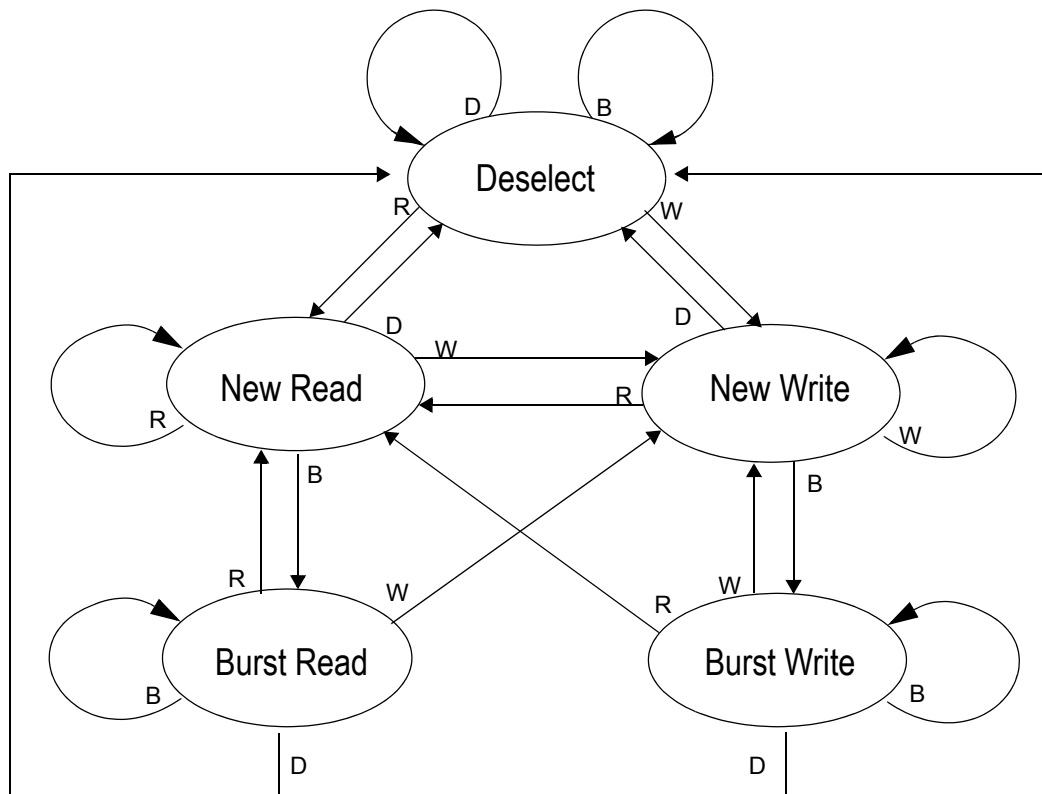
Synchronous Truth Table

Operation	Type	Address	$\overline{E1}$	E2	$\overline{E3}$	ZZ	ADV	\overline{W}	\overline{Bx}	\overline{G}	\overline{CKE}	CK	DQ	Notes
Deselect Cycle, Power Down	D	None	H	X	X	L	L	X	X	X	L	L-H	High-Z	
Deselect Cycle, Power Down	D	None	X	X	H	L	L	X	X	X	L	L-H	High-Z	
Deselect Cycle, Power Down	D	None	X	L	X	L	L	X	X	X	L	L-H	High-Z	
Deselect Cycle, Continue	D	None	X	X	X	L	H	X	X	X	L	L-H	High-Z	1
Read Cycle, Begin Burst	R	External	L	H	L	L	L	H	X	L	L	L-H	Q	
Read Cycle, Continue Burst	B	Next	X	X	X	L	H	X	X	L	L	L-H	Q	1,10
NOP/Read, Begin Burst	R	External	L	H	L	L	L	H	X	H	L	L-H	High-Z	2
Dummy Read, Continue Burst	B	Next	X	X	X	L	H	X	X	H	L	L-H	High-Z	1,2,10
Write Cycle, Begin Burst	W	External	L	H	L	L	L	L	L	X	L	L-H	D	3
Write Cycle, Continue Burst	B	Next	X	X	X	L	H	X	L	X	L	L-H	D	1,3,10
NOP/Write Abort, Begin Burst	W	None	L	H	L	L	L	L	H	X	L	L-H	High-Z	2,3
Write Abort, Continue Burst	B	Next	X	X	X	L	H	X	H	X	L	L-H	High-Z	1,2,3,10
Clock Edge Ignore, Stall		Current	X	X	X	L	X	X	X	X	H	L-H	-	4
Sleep Mode		None	X	X	X	H	X	X	X	X	X	X	High-Z	

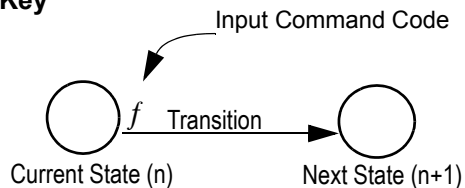
Notes:

- Continue Burst cycles, whether read or write, use the same control inputs; a Deselect continue cycle can only be entered into if a Deselect cycle is executed first
- Dummy read and write abort can be considered NOPs because the SRAM performs no operation. A Write abort occurs when the \overline{W} pin is sampled low but no Byte Write pins are active, so no Write operation is performed.
- \overline{G} can be wired low to minimize the number of control signals provided to the SRAM. Output drivers will automatically turn off during Write cycles.
- If CKE High occurs during a pipelined read cycle, the DQ bus will remain active (Low Z). If \overline{CKE} High occurs during a write cycle, the bus will remain in High Z.
- X = Don't Care; H = Logic High; L = Logic Low; \overline{Bx} = High = All Byte Write signals are high; \overline{Bx} = Low = One or more Byte/Write signals are Low
- All inputs, except \overline{G} and ZZ must meet setup and hold times of rising clock edge.
- Wait states can be inserted by setting CKE high.
- This device contains circuitry that ensures all outputs are in High Z during power-up.
- A 2-bit burst counter is incorporated.
- The address counter is incremented for all Burst continue cycles.

Pipeline and Flow Through Read-Write Control State Diagram

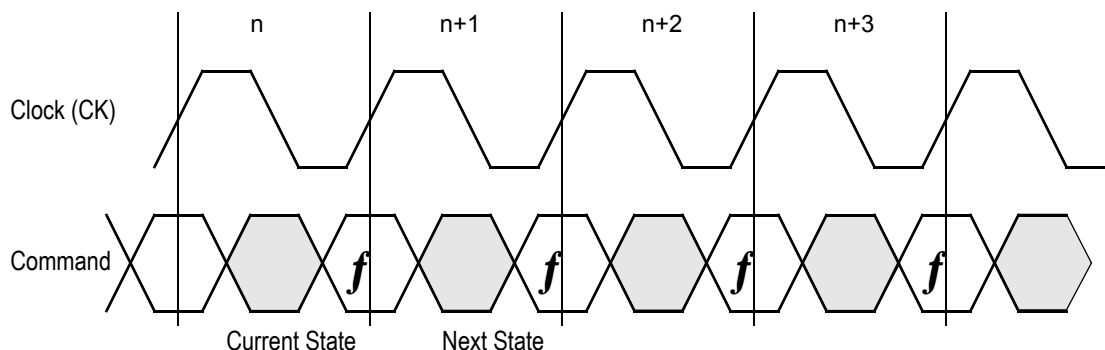


Key



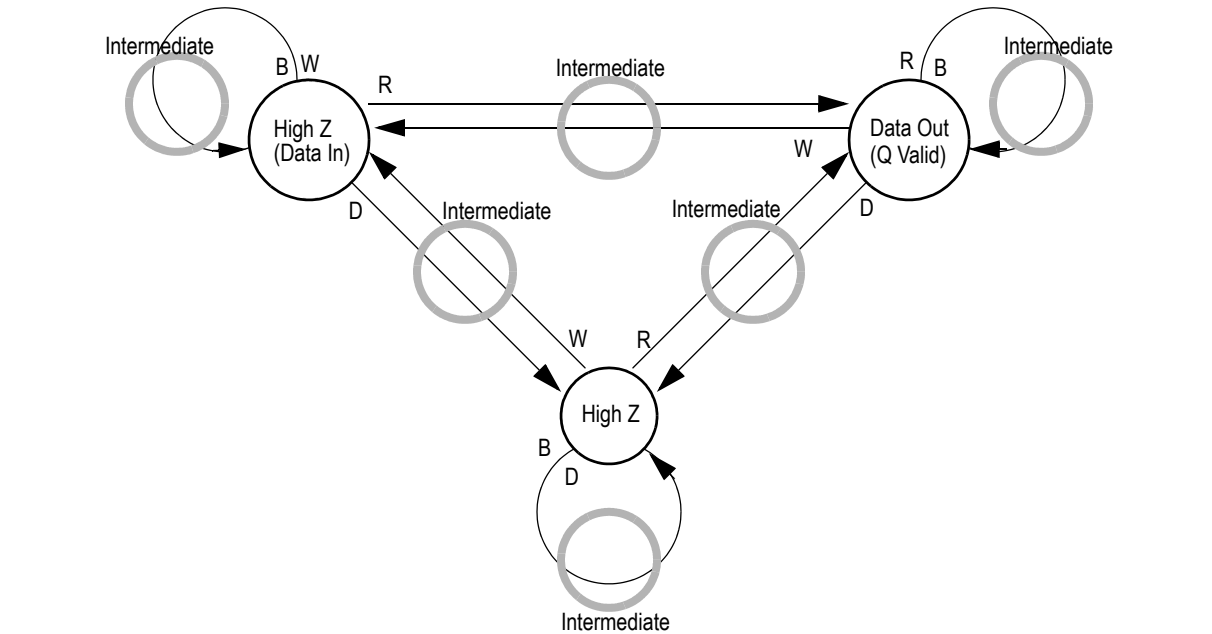
Notes

1. The Hold command ($\overline{\text{CKE}}$ Low) is not shown because it prevents any state change.
2. W, R, B and D represent input command codes, as indicated in the Synchronous Truth Table.

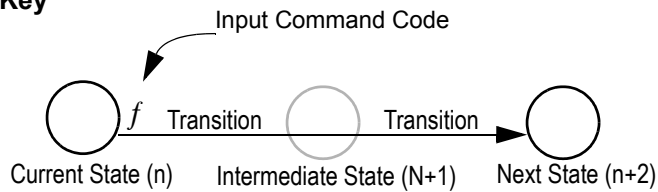


Current State and Next State Definition for Pipelined and Flow Through Read/Write Control State Diagram

Pipeline Mode Data I/O State Diagram

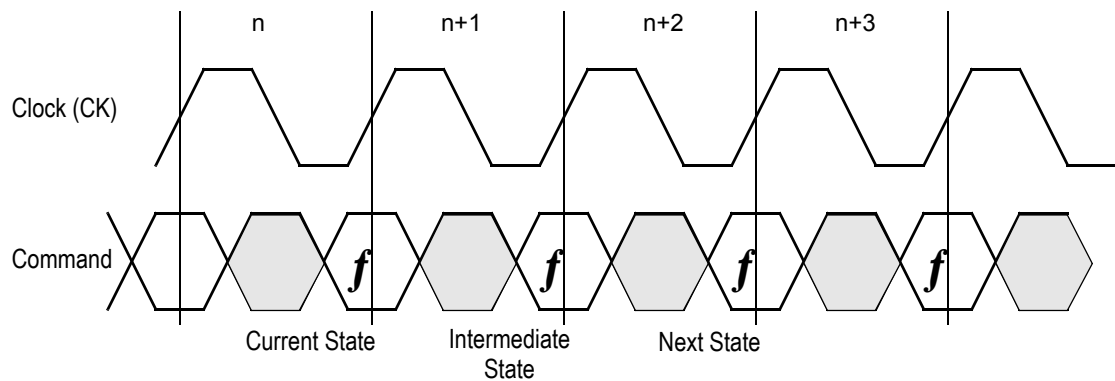


Key



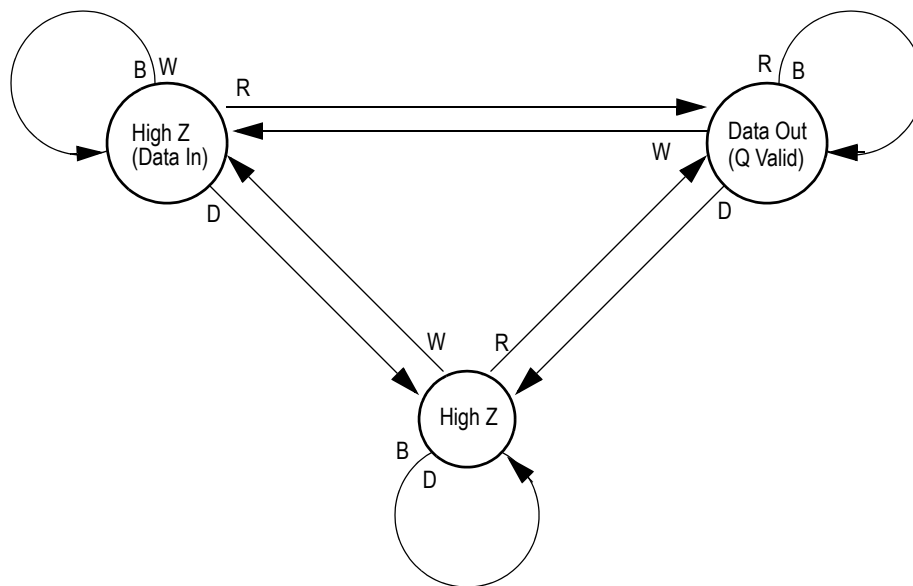
Notes

1. The Hold command ($\overline{\text{CKE}}$ Low) is not shown because it prevents any state change.
2. W, R, B, and D represent input command codes as indicated in the Truth Tables.

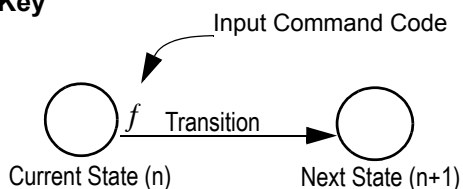


Current State and Next State Definition for Pipeline Mode Data I/O State Diagram

Flow Through Mode Data I/O State Diagram

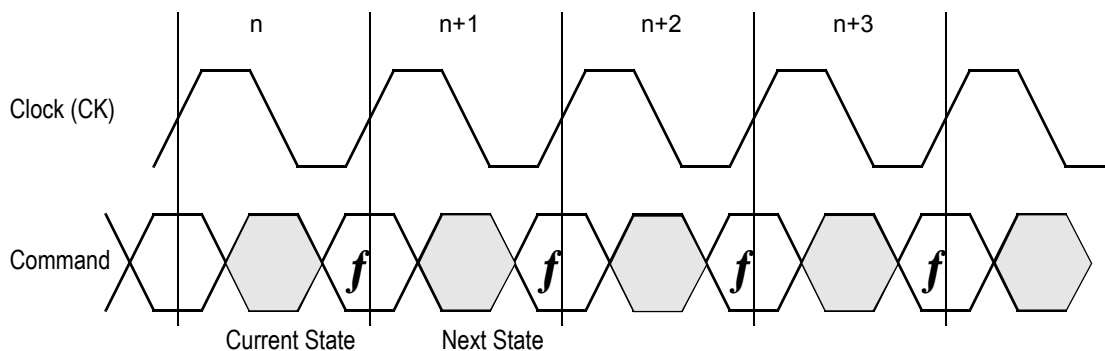


Key



Notes

1. The Hold command ($\overline{\text{CKE}}$ Low) is not shown because it prevents any state change.
2. W, R, B, and D represent input command codes as indicated in the Truth Tables.



Current State and Next State Definition for: Pipeline and Flow Through Read Write Control State Diagram

Burst Cycles

Although NBT RAMs are designed to sustain 100% bus bandwidth by eliminating turnaround cycle when there is transition from read to write, multiple back-to-back reads or writes may also be performed. NBT SRAMs provide an on-chip burst address generator that can be utilized, if desired, to further simplify burst read or write implementations. The ADV control pin, when driven high, commands the SRAM to advance the internal address counter and use the counter generated address to read or write the SRAM. The starting address for the first cycle in a burst cycle series is loaded into the SRAM by driving the ADV pin low, into Load mode.

Burst Order

The burst address counter wraps around to its initial state after four addresses (the loaded address and three more) have been accessed. The burst sequence is determined by the state of the Linear Burst Order pin ($\overline{\text{LBO}}$). When this pin is Low, a linear burst sequence is selected. When the RAM is installed with the LBO pin tied high, Interleaved burst sequence is selected. See the tables below for details.

Mode Pin Functions

Mode Name	Pin Name	State	Function
Burst Order Control	$\overline{\text{LBO}}$	L	Linear Burst
		H or NC	Interleaved Burst
Output Register Control	$\overline{\text{FT}}$	L	Flow Through
		H or NC	Pipeline
Power Down Control	ZZ	L or NC	Active
		H	Standby, $I_{DD} = I_{SB}$

Note:

There are pull-up devices on the $\overline{\text{LBO}}$ and $\overline{\text{FT}}$ pins and a pull down device on the ZZ pin, so those input pins can be unconnected and the chip will operate in the default states as specified in the above table.

Burst Counter Sequences

Linear Burst Sequence

	A[1:0]	A[1:0]	A[1:0]	A[1:0]
1st address	00	01	10	11
2nd address	01	10	11	00
3rd address	10	11	00	01
4th address	11	00	01	10

Note: The burst counter wraps to initial state on the 5th clock.

Interleaved Burst Sequence

	A[1:0]	A[1:0]	A[1:0]	A[1:0]
1st address	00	01	10	11
2nd address	01	00	11	10
3rd address	10	11	00	01
4th address	11	10	01	00

Note: The burst counter wraps to initial state on the 5th clock.

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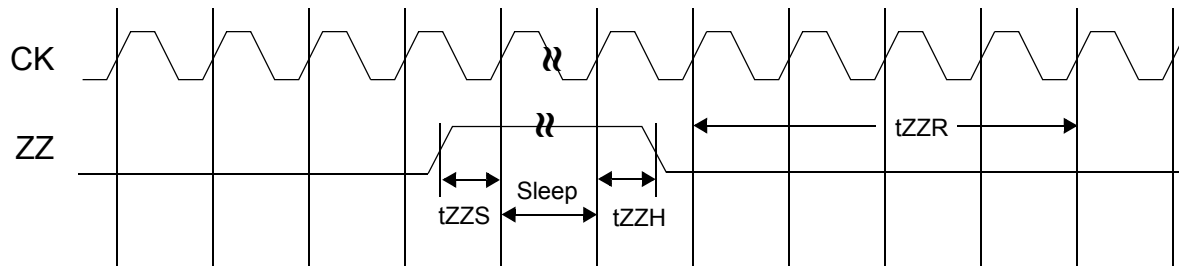
Sleep Mode

During normal operation, ZZ must be pulled low, either by the user or by its internal pull down resistor. When ZZ is pulled high, the SRAM will enter a Power Sleep mode after 2 cycles. At this time, internal state of the SRAM is preserved. When ZZ returns to low, the SRAM operates normally after 2 cycles of wake up time.

Sleep mode is a low current, power-down mode in which the device is deselected and current is reduced to I_{SB2} . The duration of

Sleep mode is dictated by the length of time the ZZ is in a High state. After entering Sleep mode, all inputs except ZZ become disabled and all outputs go to High-Z. The ZZ pin is an asynchronous, active high input that causes the device to enter Sleep mode. When the ZZ pin is driven high, I_{SB2} is guaranteed after the time t_{ZZI} is met. Because ZZ is an asynchronous input, pending operations or operations in progress may not be properly completed if ZZ is asserted. Therefore, Sleep mode must not be initiated until valid pending operations are completed. Similarly, when exiting Sleep mode during t_{ZZR} , only a Deselect or Read commands may be applied while the SRAM is recovering from Sleep mode.

Sleep Mode Timing Diagram



Designing for Compatibility

The GSI NBT SRAMs offer users a configurable selection between Flow Through mode and Pipeline mode via the \overline{FT} signal found on Pin 14. Not all vendors offer this option, however most mark Pin 14 as V_{DD} or V_{DDQ} on pipelined parts and V_{SS} on flow through parts. GSI NBT SRAMs are fully compatible with these sockets.

Pin 66, a No Connect (NC) on GSI's GS880Z18/36 NBT SRAM, the Parity Error open drain output on GSI's GS881Z18/36 NBT SRAM, is often marked as a power pin on other vendor's NBT-compatible SRAMs. Specifically, it is marked V_{DD} or V_{DDQ} on pipelined parts and V_{SS} on flow through parts. Users of GSI NBT devices who are not actually using the ByteSafe™ parity feature may want to design the board site for the RAM with Pin 66 tied high through a 1k ohm resistor in Pipeline mode applications or tied low in Flow Through mode applications in order to keep the option to use non-configurable devices open. By using the pull-up resistor, rather than tying the pin to one of the power rails, users interested in upgrading to GSI's ByteSafe NBT SRAMs (GS881Z18/36), featuring Parity Error detection and JTAG Boundary Scan, will be ready for connection to the active low, open drain Parity Error output driver at Pin 66 on GSI's TQFP ByteSafe RAMs.

Absolute Maximum Ratings

(All voltages reference to V_{SS})

Symbol	Description	Value	Unit
V_{DD}	Voltage on V_{DD} Pins	-0.5 to 4.6	V
V_{DDQ}	Voltage in V_{DDQ} Pins	-0.5 to V_{DD}	V
V_{CK}	Voltage on Clock Input Pin	-0.5 to 6	V
$V_{I/O}$	Voltage on I/O Pins	-0.5 to $V_{DDQ} + 0.5$ (≤ 4.6 V max.)	V
V_{IN}	Voltage on Other Input Pins	-0.5 to $V_{DD} + 0.5$ (≤ 4.6 V max.)	V
I_{IN}	Input Current on Any Pin	+/-20	mA
I_{OUT}	Output Current on Any I/O Pin	+/-20	mA
P_D	Package Power Dissipation	1.5	W
T_{STG}	Storage Temperature	-55 to 125	°C
T_{BIAS}	Temperature Under Bias	-55 to 125	°C

Note:

Permanent damage to the device may occur if the Absolute Maximum Ratings are exceeded. Operation should be restricted to Recommended Operating Conditions. Exposure to conditions exceeding the Absolute Maximum Ratings, for an extended period of time, may affect reliability of this component.

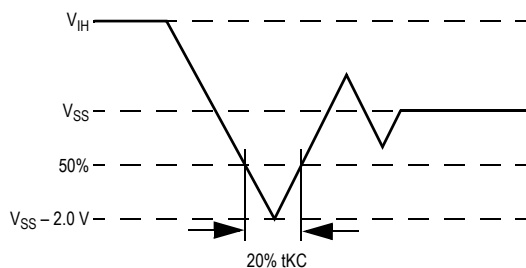
Recommended Operating Conditions

Parameter	Symbol	Min.	Typ.	Max.	Unit	Notes
Supply Voltage	V_{DD}	3.135	3.3	3.6	V	
I/O Supply Voltage	V_{DDQ}	2.375	2.5	V_{DD}	V	1
Input High Voltage	V_{IH}	1.7	—	$V_{DD} + 0.3$	V	2
Input Low Voltage	V_{IL}	-0.3	—	0.8	V	2
Ambient Temperature (Commercial Range Versions)	T_A	0	25	70	°C	3
Ambient Temperature (Industrial Range Versions)	T_A	-40	25	85	°C	3

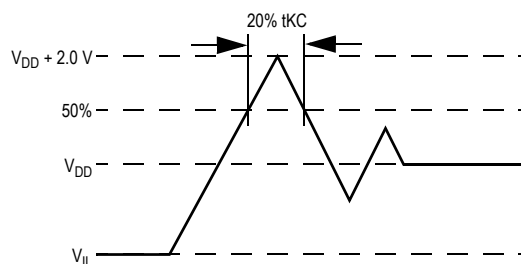
Notes:

- Unless otherwise noted, all performance specifications quoted are evaluated for worst case at both $2.75\text{ V} \leq V_{DDQ} \leq 2.375\text{ V}$ (i.e., 2.5 V I/O) and $3.6\text{ V} \leq V_{DDQ} \leq 3.135\text{ V}$ (i.e., 3.3 V I/O), and quoted at whichever condition is worst case.
- This device features input buffers compatible with both 3.3 V and 2.5 V I/O drivers.
- Most speed grades and configurations of this device are offered in both Commercial and Industrial Temperature ranges. The part number of Industrial Temperature Range versions end the character "I". Unless otherwise noted, all performance specifications quoted are evaluated for worst case in the temperature range marked on the device.
- Input Under/overshoot voltage must be $-2\text{ V} > V_i < V_{DD} + 2\text{ V}$ with a pulse width not to exceed 20% tKC.

Undershoot Measurement and Timing



Overshoot Measurement and Timing



Capacitance

($T_A = 25^\circ\text{C}$, $f = 1\text{ MHz}$, $V_{DD} = 3.3\text{ V}$)

Parameter	Symbol	Test conditions	Typ.	Max.	Unit
Input Capacitance	C_{IN}	$V_{IN} = 0\text{ V}$	4	5	pF
Input/Output Capacitance	$C_{I/O}$	$V_{OUT} = 0\text{ V}$	6	7	pF

Note: These parameters are sample tested.

Package Thermal Characteristics

Rating	Layer Board	Symbol	Max	Unit	Notes
Junction to Ambient (at 200 lfm)	single	$R_{\Theta JA}$	40	$^\circ\text{C/W}$	1,2
Junction to Ambient (at 200 lfm)	four	$R_{\Theta JA}$	24	$^\circ\text{C/W}$	1,2
Junction to Case (TOP)	—	$R_{\Theta JC}$	9	$^\circ\text{C/W}$	3

Notes:

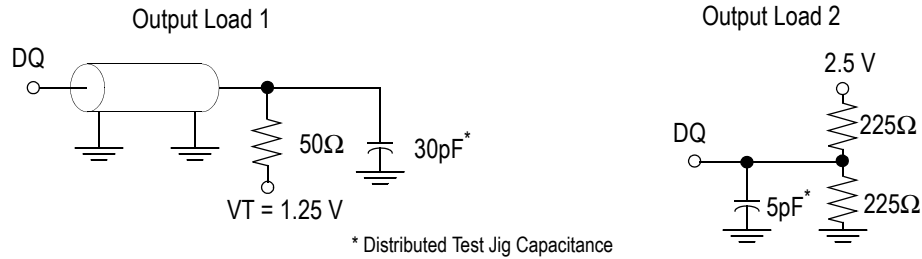
- Junction temperature is a function of SRAM power dissipation, package thermal resistance, mounting board temperature, ambient. Temperature air flow, board density, and PCB thermal resistance.
- SCMI G-38-87
- Average thermal resistance between die and top surface, MIL SPEC-883, Method 1012.1

AC Test Conditions

Parameter	Conditions
Input high level	2.3 V
Input low level	0.2 V
Input slew rate	1 V/ns
Input reference level	1.25 V
Output reference level	1.25 V
Output load	Fig. 1 & 2

Notes:

1. Include scope and jig capacitance.
2. Test conditions as specified with output loading as shown in **Fig. 1** unless otherwise noted.
3. Output Load 2 for t_{LZ} , t_{HZ} , t_{OLZ} and t_{OHZ}
4. Device is deselected as defined by the Truth Table.



DC Electrical Characteristics

Parameter	Symbol	Test Conditions	Min	Max
Input Leakage Current (except mode pins)	I_{IL}	$V_{IN} = 0 \text{ to } V_{DD}$	-1 μA	1 μA
ZZ Input Current	I_{INZZ}	$V_{DD} \geq V_{IN} \geq V_{IH}$ $0 \text{ V} \leq V_{IN} \leq V_{IH}$	-1 μA -1 μA	1 μA 300 μA
Mode Pin Input Current	I_{INM}	$V_{DD} \geq V_{IN} \geq V_{IL}$ $0 \text{ V} \leq V_{IN} \leq V_{IL}$	-300 μA -1 μA	1 μA 1 μA
Output Leakage Current	I_{OL}	Output Disable, $V_{OUT} = 0 \text{ to } V_{DD}$	-1 μA	1 μA
Output High Voltage	V_{OH}	$I_{OH} = - \text{mA}$, $V_{DDQ} = 2.375 \text{ V}$	1.7 V	—
Output High Voltage	V_{OH}	$I_{OH} = - \text{mA}$, $V_{DDQ} = 3.135 \text{ V}$	2.4 V	—
Output Low Voltage	V_{OL}	$I_{OL} = 8 \text{ mA}$	—	0.4 V

Operating Currents

Parameter	Test Conditions	Symbol	-180		-166		-150		-100		Unit
			0 to 70°C	-40 to 85°C	0 to 70°C	-40 to 85°C	0 to 70°C	-40 to 85°C	0 to 70°C	-40 to 85°C	
Operating Current	Device Selected; All other inputs $\geq V_{IH}$ or $\leq V_{IL}$ Output open	I_{DD} Pipeline	335	345	310	320	280	290	190	200	mA
		I_{DD} Flow-Thru	210	220	190	200	165	175	135	145	mA
Standby Current	$ZZ \geq V_{DD} - 0.2\text{ V}$	I_{SB} Pipeline	20	30	20	30	20	30	20	30	mA
		I_{SB} Flow-Thru	20	30	20	30	20	30	20	30	mA
Deselect Current	Device Deselected; All other inputs $\geq V_{IH}$ or $\leq V_{IL}$	I_{DD} Pipeline	55	65	50	60	50	60	40	50	mA
		I_{DD} Flow-Thru	40	50	40	50	35	45	35	45	mA

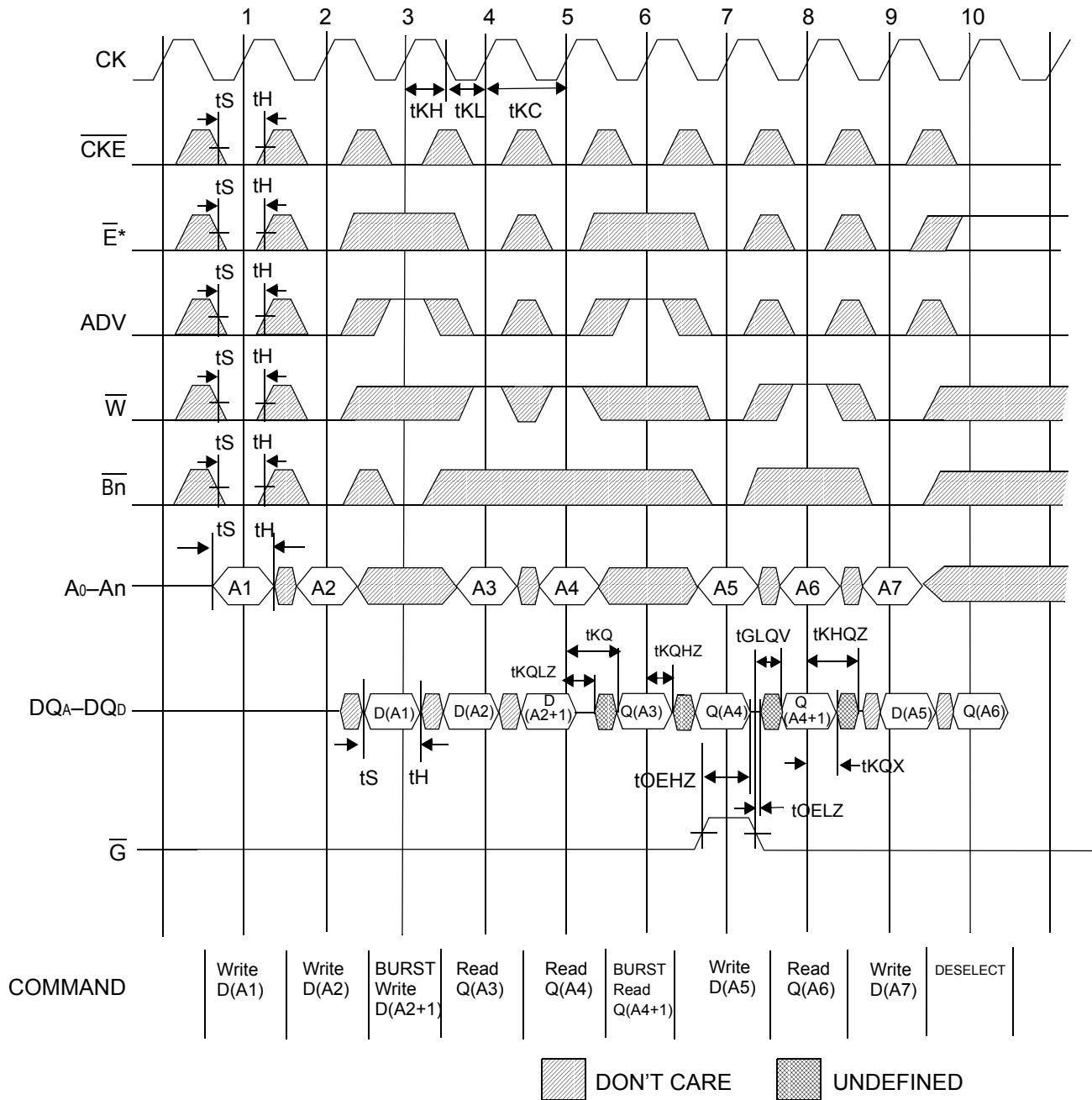
AC Electrical Characteristics

	Parameter	Symbol	-180		-166		-150		-100		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	
Pipeline	Clock Cycle Time	t _{KC}	5.5	—	6.0	—	6.7	—	10	—	ns
	Clock to Output Valid	t _{KQ}	—	3.2	—	3.5	—	3.8	—	4.5	ns
	Clock to Output Invalid	t _{KQX}	1.5	—	1.5	—	1.5	—	1.5	—	ns
	Clock to Output in Low-Z	t _{LZ} ¹	1.5	—	1.5	—	1.5	—	1.5	—	ns
Flow Through	Clock Cycle Time	t _{KC}	9.1	—	10.0	—	12.0	—	15.0	—	ns
	Clock to Output Valid	t _{KQ}	—	8.0	—	8.5	—	10.0	—	12.0	ns
	Clock to Output Invalid	t _{KQX}	3.0	—	3.0	—	3.0	—	3.0	—	ns
	Clock to Output in Low-Z	t _{LZ} ¹	3.0	—	3.0	—	3.0	—	3.0	—	ns
	Clock HIGH Time	t _{KH}	1.3	—	1.3	—	1.3	—	1.3	—	ns
	Clock LOW Time	t _{KL}	1.5	—	1.5	—	1.5	—	1.5	—	ns
	Clock to Output in High-Z	t _{HZ} ¹	1.5	3.2	1.5	3.5	1.5	3.8	1.5	5	ns
	\bar{G} to Output Valid	t _{OE}	—	3.2	—	3.5	—	3.8	—	5	ns
	\bar{G} to output in Low-Z	t _{OLZ} ¹	0	—	0	—	0	—	0	—	ns
	\bar{G} to output in High-Z	t _{OHZ} ¹	—	3.2	—	3.5	—	3.8	—	5	ns
	Setup time	t _S	1.5	—	1.5	—	1.5	—	2.0	—	ns
	Hold time	t _H	0.5	—	0.5	—	0.5	—	0.5	—	ns
	ZZ setup time	t _{ZZS} ²	5	—	5	—	5	—	5	—	ns
	ZZ hold time	t _{ZZH} ²	1	—	1	—	1	—	1	—	ns
	ZZ recovery	t _{ZZR}	20	—	20	—	20	—	20	—	ns

Notes:

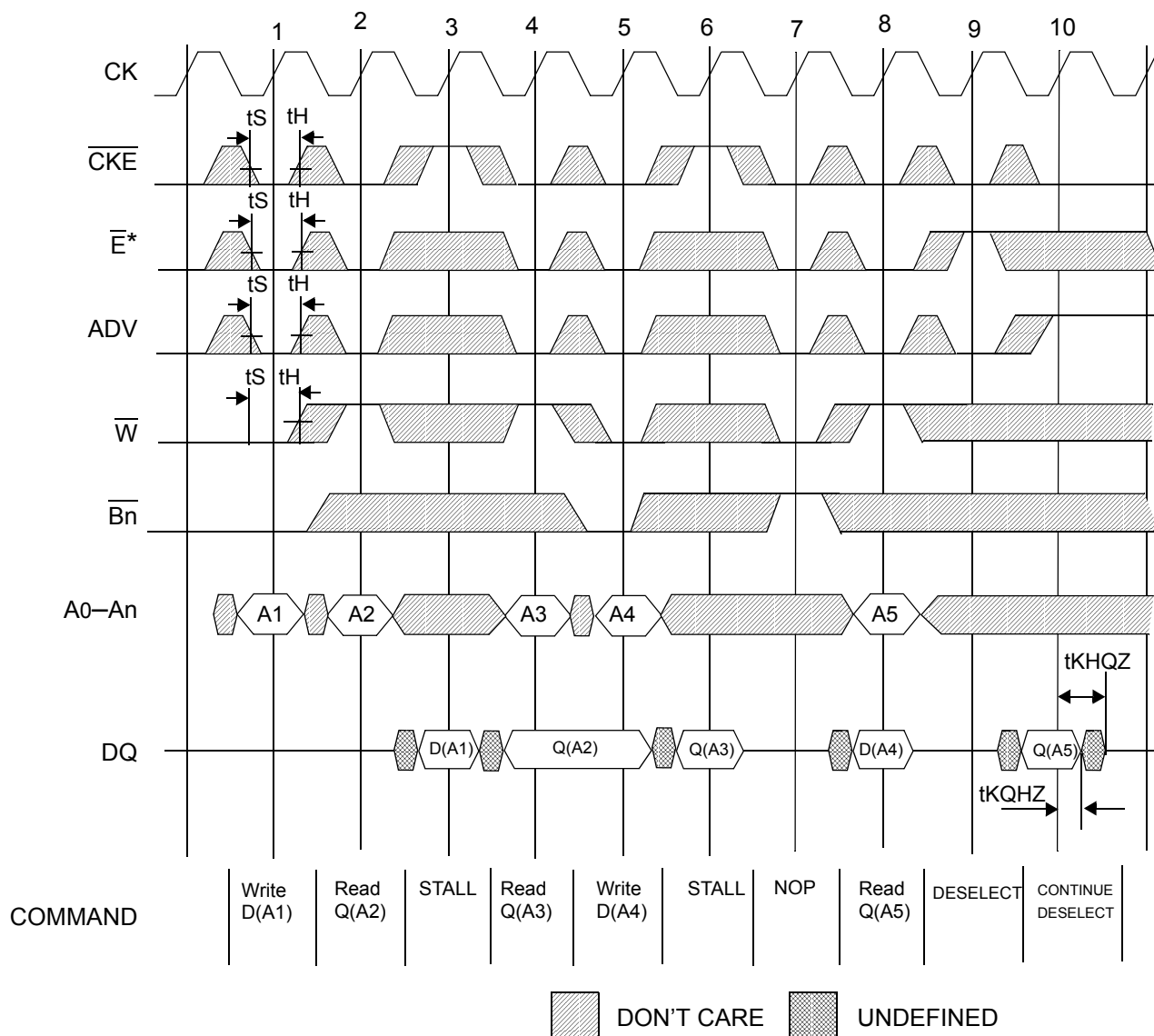
- These parameters are sampled and are not 100% tested
- ZZ is an asynchronous signal. However, In order to be recognized on any given clock cycle, ZZ must meet the specified setup and hold times as specified above.

Pipeline Mode Read/Write Cycle Timing



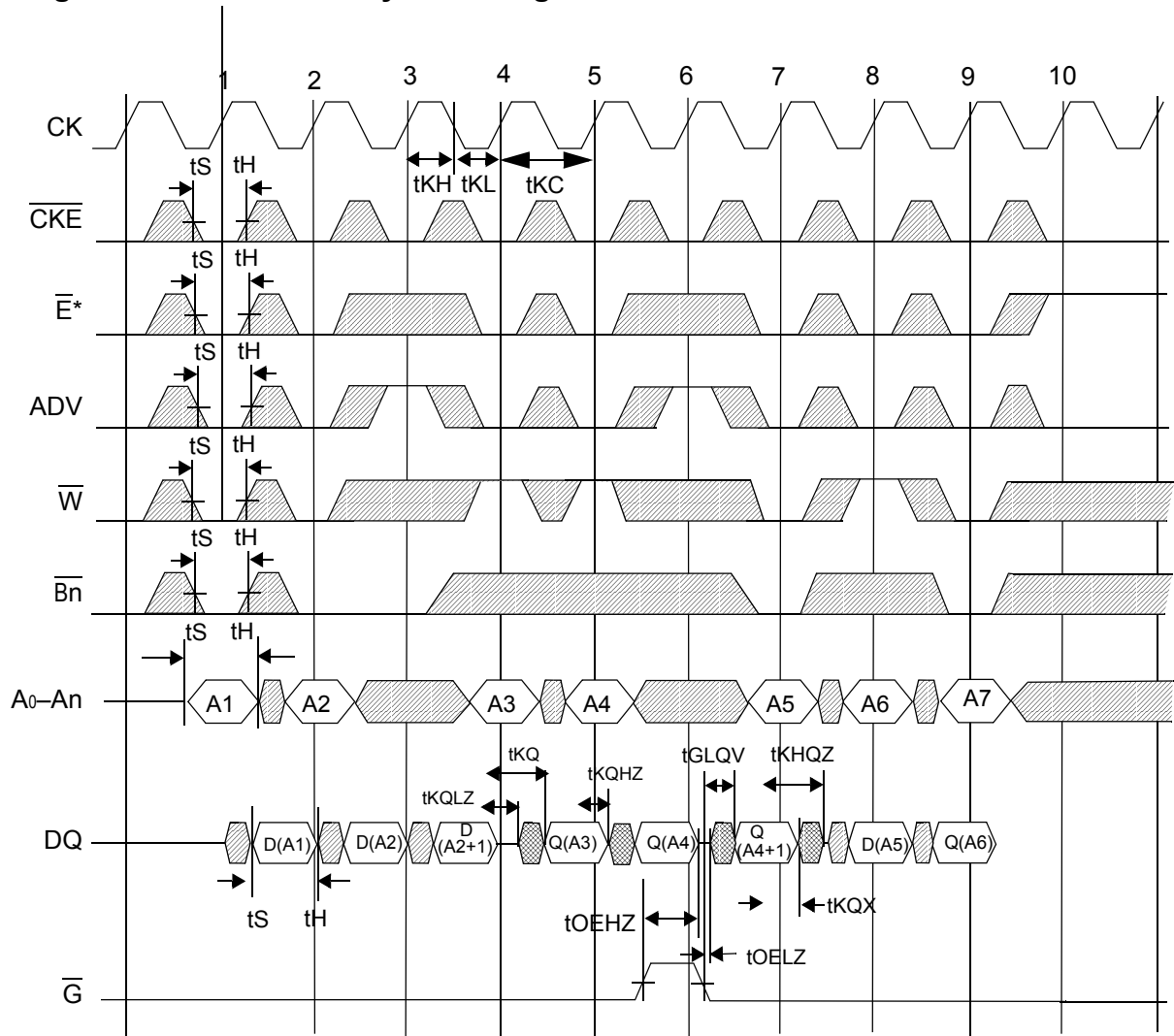
*Note: $\overline{E} = \text{High (False)}$ if $\overline{E}_1 = 1$ or $E_2 = 0$ or $\overline{E}_3 = 1$

Pipeline Mode No-Op, Stall and Deselect Timing



*Note: \overline{E} = High (False) if $\overline{E}_1 = 1$ or $E_2 = 0$ or $\overline{E}_3 = 1$

Flow Through Mode Read/Write Cycle Timing

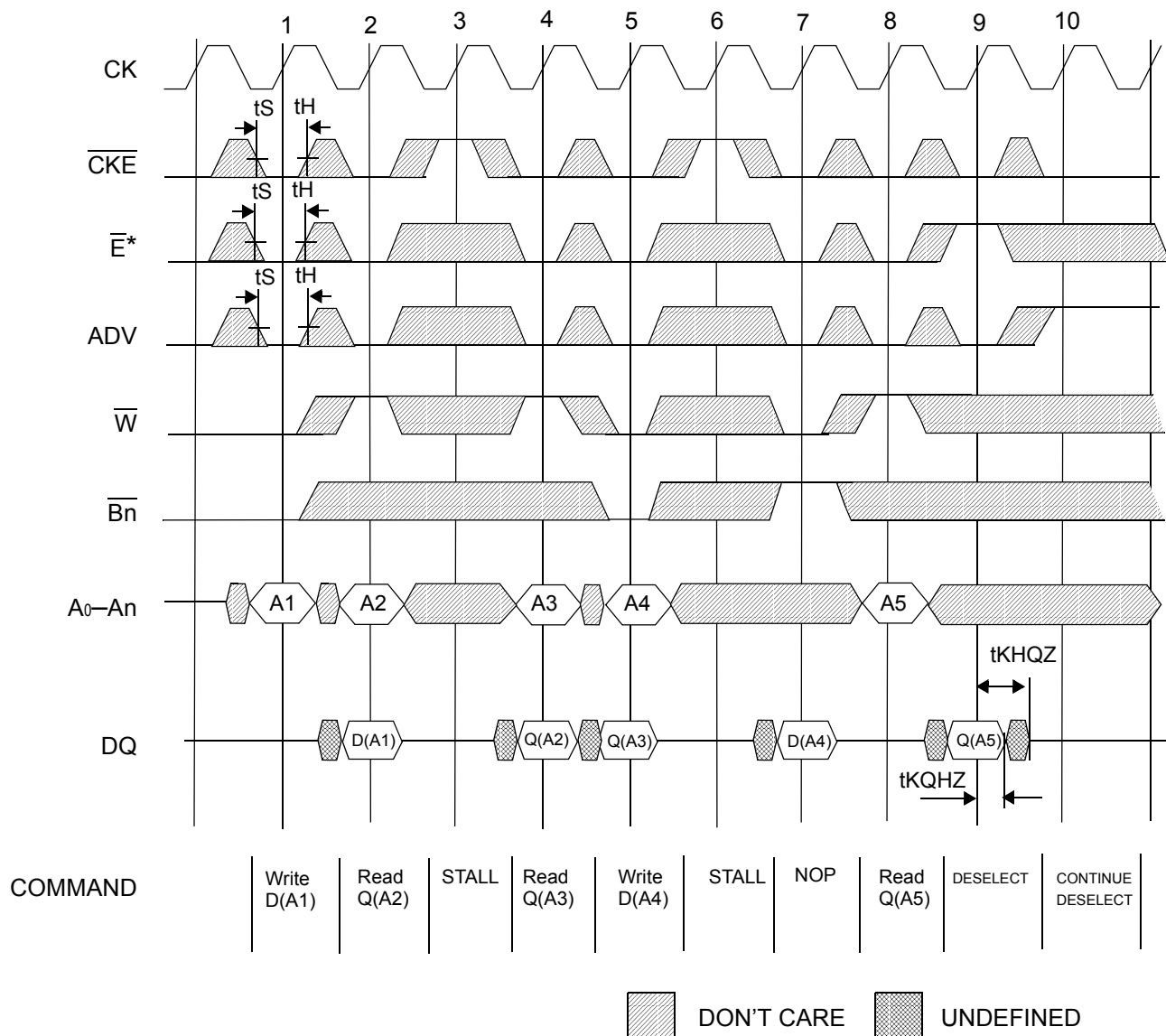


COMMAND	Write D(A1)	Write D(A2)	BURST Write D(A2+1)	Read Q(A3)	Read Q(A4)	BURST Read Q(A4+1)	Write D(A5)	Read Q(A6)	Write D(A7)	DESELECT
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DON'T CARE
 UNDEFINED

*Note: \bar{E} = High (False) if $\bar{E}_1 = 1$ or $E_2 = 0$ or $\bar{E}_3 = 1$

Flow Through Mode No-Op, Stall and Deselect Timing



*Note: \overline{E} = High (False) if $\overline{E}_1 = 1$ or $E_2 = 0$ or $\overline{E}_3 = 1$

JTAG Port Operation

Overview

The JTAG Port on this RAM operates in a manner consistent with IEEE Standard 1149.1-1990, a serial boundary scan interface standard (commonly referred to as JTAG), but does not implement all of the functions required for 1149.1 compliance. Some functions have been modified or eliminated because they can slow the RAM. Nevertheless, the RAM supports 1149.1-1990 TAP (Test Access Port) Controller architecture, and can be expected to function in a manner that does not conflict with the operation of Standard 1149.1 compliant devices. The JTAG Port interfaces with conventional TTL / CMOS logic level signaling.

Disabling the JTAG Port

It is possible to use this device without utilizing the JTAG port. The port is reset at power-up and will remain inactive unless clocked. TCK, TDI, and TMS are designed with internal pull-up circuits. To assure normal operation of the RAM with the JTAG Port unused, TCK, TDI, and TMS may be left floating or tied to either V_{DD} or V_{SS} . TDO should be left unconnected.

JTAG Pin Descriptions

Pin	Pin Name	I/O	Description
TCK	Test Clock	In	Clocks all TAP events. All inputs are captured on the rising edge of TCK and all outputs propagate from the falling edge of TCK.
TMS	Test Mode Select	In	The TMS input is sampled on the rising edge of TCK. This is the command input for the TAP controller state machine. An undriven TMS input will produce the same result as a logic one input level.
TDI	Test Data In	In	The TDI input is sampled on the rising edge of TCK. This is the input side of the serial registers placed between TDI and TDO. The register placed between TDI and TDO is determined by the state of the TAP Controller state machine and the instruction that is currently loaded in the TAP Instruction Register (refer to the TAP Controller State Diagram). An undriven TDI pin will produce the same result as a logic one input level.
TDO	Test Data Out	Out	Output that is active depending on the state of the TAP state machine. Output changes in response to the falling edge of TCK. This is the output side of the serial registers placed between TDI and TDO.

Note:

This device does not have a TRST (TAP Reset) pin. TRST is optional in IEEE 1149.1. The Test-Logic-Reset state is entered while TMS is held high for five rising edges of TCK. The TAP Controller is also reset automatically at power-up.

JTAG Port Registers

Overview

The various JTAG registers, referred to as TAP Registers, are selected (one at a time) via the sequences of 1s and 0s applied to TMS as TCK is strobed. Each of the TAP Registers are serial shift registers that capture serial input data on the rising edge of TCK and push serial data out on the next falling edge of TCK. When a register is selected it is placed between the TDI and TDO pins.

Instruction Register

The Instruction Register holds the instructions that are executed by the TAP controller when it is moved into the Run, Test/Idle or the various data register states. Instructions are 3 bits long. The Instruction Register can be loaded when it is placed between the TDI and TDO pins. The Instruction Register is automatically preloaded with the IDCODE instruction at power-up or whenever the controller is placed in Test-Logic-Reset state.

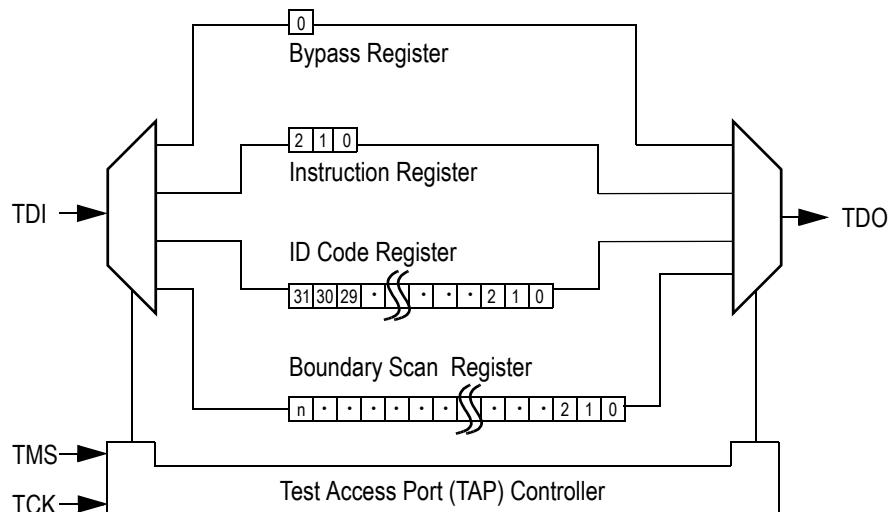
Bypass Register

The Bypass Register is a single-bit register that can be placed between TDI and TDO. It allows serial test data to be passed through the RAMs JTAG Port to another device in the scan chain with as little delay as possible.

Boundary Scan Register

Boundary Scan Register is a collection of flip flops that can be preset by the logic level found on the RAM's input or I/O pins. The flip flops are then daisy chained together so the levels found can be shifted serially out of the JTAG Port's TDO pin. The Boundary Scan Register also includes a number of place holder flip flops (always set to a logic 1). The relationship between the device pins and the bits in the Boundary Scan Register is described in the Scan Order Table following. The Boundary Scan Register, under the control of the TAP Controller, is loaded with the contents of the RAM's I/O ring when the controller is in Capture-DR state and then is placed between the TDI and TDO pins when the controller is moved to Shift-DR state. Two TAP instructions can be used to activate the Boundary Scan Register.

JTAG TAP Block Diagram



Identification (ID) Register

The ID Register is a 32-bit register that is loaded with a device and vendor specific 32-bit code when the controller is put in Capture-DR state with the IDCODE command loaded in the Instruction Register. The code is loaded from a 32-bit on-chip ROM. It describes various attributes of the RAM as indicated below. The register is then placed between the TDI and TDO pins when the controller is moved into Shift-DR state. Bit 0 in the register is the LSB and the first to reach TDO when shifting begins.

ID Register Contents

	Die Revision Code				Not Used												I/O Configuration				GSI Technology JEDEC Vendor ID Code												Presence Register
Bit #	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
x36	X	X	X	X	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	0	0	0	1	1	0	1	1	0	0	1	1	
x18	X	X	X	X	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	0	0	0	1	1	0	1	1	0	0	1	1	

Tap Controller Instruction Set

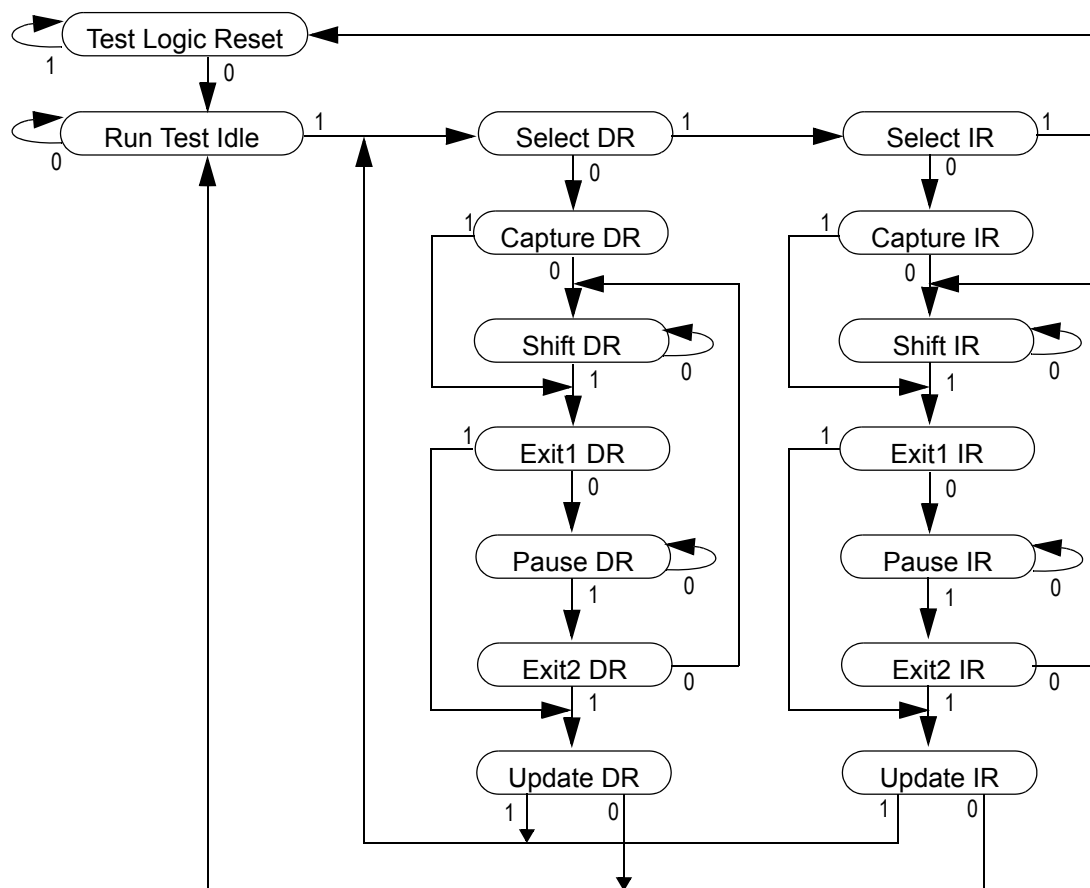
Overview

There are two classes of instructions defined in the Standard 1149.1-1990; the standard (Public) instructions, and device specific

(Private) instructions. Some Public instructions, are mandatory for 1149.1 compliance. Optional Public instructions must be implemented in prescribed ways. Although the TAP controller in this device follows the 1149.1 conventions, it is not 1194.1-compliant because some of the mandatory instructions are not fully implemented. The TAP on this device may be used to monitor all input and I/O pads, but cannot be used to load address, data or control signals into the RAM or to preload the I/O buffers. This device will not perform EXTEST, INTEST or the SAMPLE/PRELOAD command.

When the TAP controller is placed in Capture-IR state the two least significant bits of the instruction register are loaded with 01. When the controller is moved to the Shift-IR state the Instruction Register is placed between TDI and TDO. In this state the desired instruction is serially loaded through the TDI input (while the previous contents are shifted out at TDO). For all instructions, the TAP executes newly loaded instructions only when the controller is moved to Update-IR state. The TAP instruction set for this device is listed in the following table.

JTAG Tap Controller State Diagram



Instruction Descriptions

BYPASS

When the BYPASS instruction is loaded in the Instruction Register the Bypass Register is placed between TDI and TDO. This occurs when the TAP controller is moved to the Shift-DR state. This allows the board level scan path to be shortened to facilitate testing of other devices in the scan path.

SAMPLE/PRELOAD

SAMPLE/PRELOAD is a Standard 1149.1 mandatory public instruction. When the SAMPLE/PRELOAD instruction is loaded in the Instruction Register, moving the TAP controller into the Capture-DR state loads the data in the RAMs input and I/O buffers into the Boundary Scan

Register. Because the RAM clock is independent from the TAP Clock (TCK) it is possible for the TAP to attempt to capture the I/O ring contents while the input buffers are in transition (i.e. in a metastable state). Although allowing the TAP to sample metastable inputs will not harm the device, repeatable results cannot be expected. RAM input signals must be stabilized for long enough to meet the TAPs input data capture set-up plus hold time (t_{TS} plus t_{TH}). The RAMs clock inputs need not be paused for any other TAP operation except capturing the I/O ring contents into the Boundary Scan Register. Moving the controller to Shift-DR state then places the boundary scan register between the TDI and TDO pins. Because the PRELOAD portion of the command is not implemented in this device, moving the controller to the Update-DR state with the SAMPLE / PRELOAD instruction loaded in the Instruction Register has the same effect as the Pause-DR command. This functionality is not Standard 1149.1-compliant.

EXTEST

EXTEST is an IEEE 1149.1 mandatory public instruction. It is to be executed whenever the instruction register, whatever length it may be in the device, is loaded with all logic 0s. EXTEST is not implemented in this device. Therefore, this device is not 1149.1-compliant. Nevertheless, this RAM's TAP does respond to an all zeros instruction, as follows. With the EXTEST (000) instruction loaded in the instruction register the RAM responds just as it does in response to the BYPASS instruction described above.

IDCODE

The IDCODE instruction causes the ID ROM to be loaded into the ID register when the controller is in Capture-DR mode and places the ID register between the TDI and TDO pins in Shift-DR mode. The IDCODE instruction is the default instruction loaded in at power up and any time the controller is placed in the Test-Logic-Reset state.

SAMPLE-Z

If the SAMPLE-Z instruction is loaded in the instruction register, all RAM outputs are forced to an inactive drive state (high-Z) and the Boundary Scan Register is connected between TDI and TDO when the TAP controller is moved to the Shift-DR state.

RFU

These instructions are Reserved for Future Use. In this device they replicate the BYPASS instruction.

JTAG TAP Instruction Set Summary

Instruction	Code	Description	Notes
EXTEST	000	Replicates BYPASS instruction. Places Bypass Register between TDI and TDO. This RAM does not implement 1149.1 EXTEST function. *Not 1149.1 Compliant *	1
IDCODE	001	Preloads ID Register and places it between TDI and TDO.	1, 2
SAMPLE-Z	010	Captures I/O ring contents. Places the Boundary Scan Register between TDI and TDO. Forces all RAM output drivers to High-Z.	1
RFU	011	Do not use this instruction; Reserved for Future Use. Replicates BYPASS instruction. Places Bypass Register between TDI and TDO.	1
SAMPLE/ PRELOAD	100	Captures I/O ring contents. Places the Boundary Scan Register between TDI and TDO. This RAM does not implement 1149.1 PRELOAD function. *Not 1149.1 Compliant *	1
GSI	101	GSI private instruction.	1
RFU	110	Do not use this instruction; Reserved for Future Use. Replicates BYPASS instruction. Places Bypass Register between TDI and TDO.	1
BYPASS	111	Places Bypass Register between TDI and TDO.	1

Notes:

1. Instruction codes expressed in binary, MSB on left, LSB on right.
2. Default instruction automatically loaded at power-up and in test-logic-reset state.

JTAG Port Recommended Operating Conditions and DC Characteristics

Parameter	Symbol	Min.	Max.	Unit	Notes
Test Port Input High Voltage	V_{IHT}	1.7	$V_{DD} + 0.3$	V	1, 2
Test Port Input Low Voltage	V_{ILT}	-0.3	0.8	V	1, 2
TMS, TCK and TDI Input Leakage Current	I_{INTH}	-300	1	uA	3
TMS, TCK and TDI Input Leakage Current	I_{INTL}	-1	1	uA	4
TDO Output Leakage Current	I_{OLT}	-1	1	uA	5
Test Port Output High Voltage	V_{OHT}	2.4	—	V	6, 7
Test Port Output Low Voltage	V_{OLT}	—	0.4	V	6, 8

Notes:

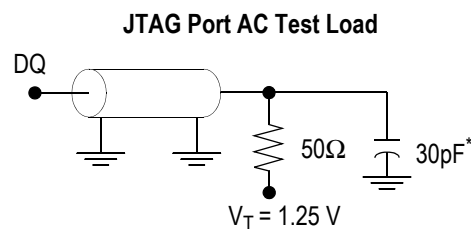
1. This device features input buffers compatible with both 3.3 V and 2.5 V I/O drivers.
2. Input Under/overshoot voltage must be $-2\text{ V} > V_i < V_{DD} + 2\text{ V}$ with a pulse width not to exceed 20% t_{TKC} .
3. $V_{DD} \geq V_{IN} \geq V_{IL}$
4. $0\text{ V} \leq V_{IN} \leq V_{IL}$
5. Output Disable, $V_{OUT} = 0$ to V_{DD}
6. The TDO output driver is served by the V_{DD} supply.
7. $I_{OH} = -4\text{ mA}$
8. $I_{OL} = +4\text{ mA}$

JTAG Port AC Test Conditions

Parameter	Conditions
Input high level	2.3 V
Input low level	0.2 V
Input slew rate	1 V/ns
Input reference level	1.25 V
Output reference level	1.25 V

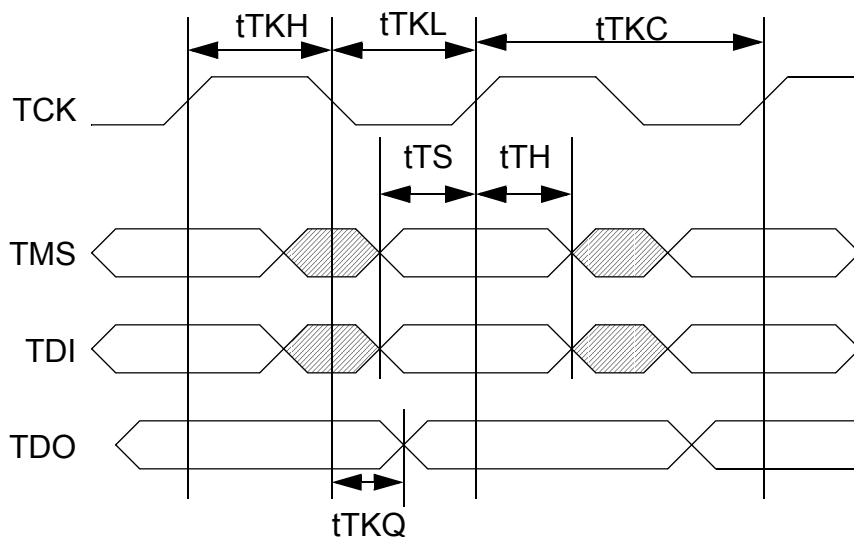
Notes:

1. Include scope and jig capacitance.



* Distributed Test Jig Capacitance

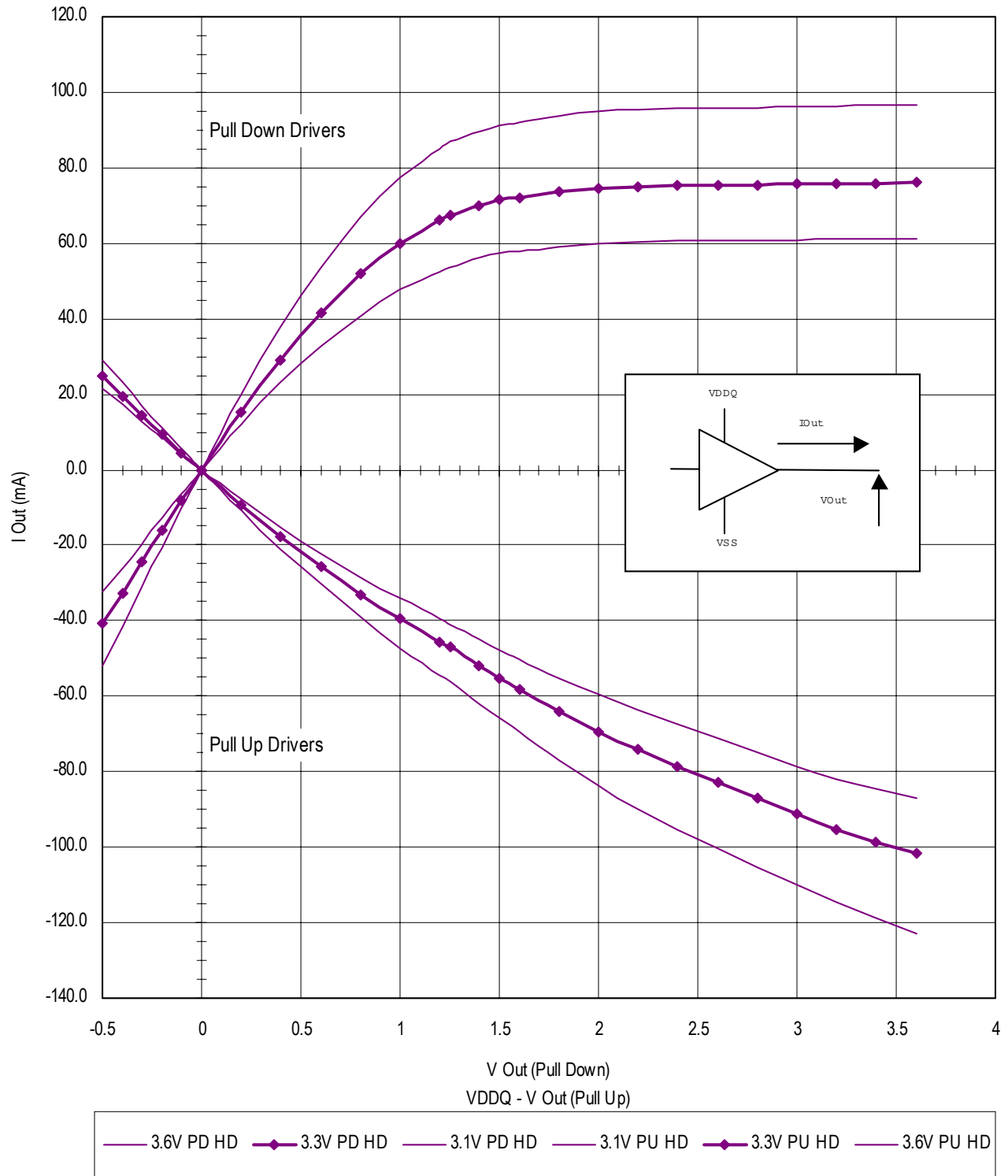
JTAG Port Timing Diagram



JTAG Port AC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
TCK Cycle Time	t_{TKC}	20	—	ns
TCK Low to TDO Valid	t_{TKQ}	—	10	ns
TCK High Pulse Width	t_{TKH}	10	—	ns
TCK Low Pulse Width	t_{TKL}	10	—	ns
TDI & TMS Set Up Time	t_{TS}	5	—	ns
TDI & TMS Hold Time	t_{TH}	5	—	ns

Output Driver Characteristics



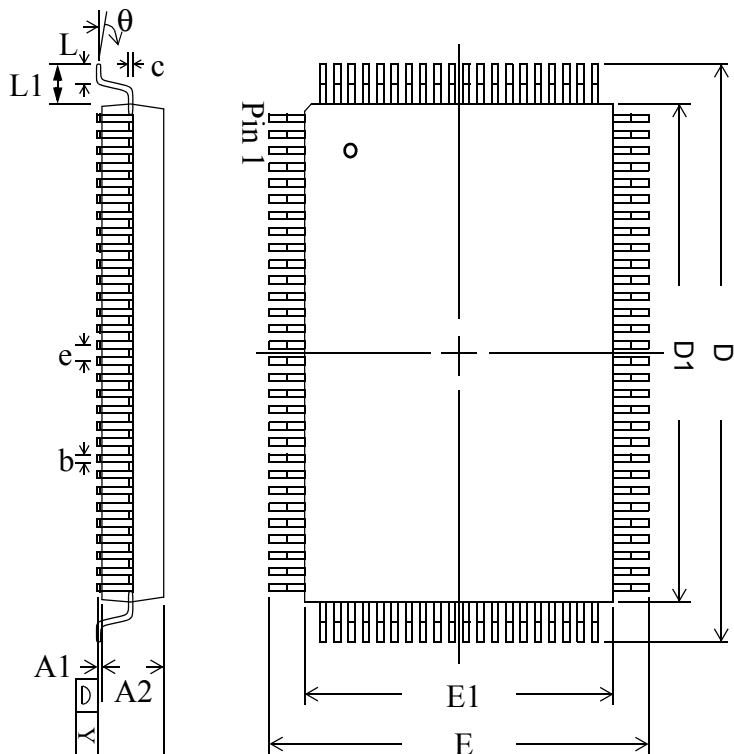
BPR 1999.05.18

TQFP Package Drawing

Symbol	Description	Min.	Nom.	Max
A1	Standoff	0.05	0.10	0.15
A2	Body Thickness	1.35	1.40	1.45
b	Lead Width	0.20	0.30	0.40
c	Lead Thickness	0.09	—	0.20
D	Terminal Dimension	21.9	22.0	22.1
D1	Package Body	19.9	20.0	20.1
E	Terminal Dimension	15.9	16.0	16.1
E1	Package Body	13.9	14.0	14.1
e	Lead Pitch	—	0.65	—
L	Foot Length	0.45	0.60	0.75
L1	Lead Length	—	1.00	—
Y	Coplanarity	—	—	0.10
θ	Lead Angle	0°	—	7°

Notes:

1. All dimensions are in millimeters (mm).
2. Package width and length do not include mold protrusion.



BPR 1999.05.18

Ordering Information—GSI NBT Synchronous SRAM

Org	Part Number ¹	Type	Package	Speed ² (MHz/ns)	T _A ³	Status
256K x 18	GS841Z18AT-180	NBT Pipeline/Flow Through	TQFP	180/8	C	
256K x 18	GS841Z18AT-166	NBT Pipeline/Flow Through	TQFP	166/8.5	C	
256K x 18	GS841Z18AT-150	NBT Pipeline/Flow Through	TQFP	150/10	C	
256K x 18	GS841Z18AT-100	NBT Pipeline/Flow Through	TQFP	100/12	C	
128K x 36	GS841Z36AT-180	NBT Pipeline/Flow Through	TQFP	180/8	C	
128K x 36	GS841Z36AT-166	NBT Pipeline/Flow Through	TQFP	166/8.5	C	
128K x 36	GS841Z36AT-150	NBT Pipeline/Flow Through	TQFP	150/10	C	
128K x 36	GS841Z36AT-100	NBT Pipeline/Flow Through	TQFP	100/12	C	
256K x 18	GS841Z18AT-180I	NBT Pipeline/Flow Through	TQFP	180/8	I	
256K x 18	GS841Z18AT-166I	NBT Pipeline/Flow Through	TQFP	166/8.5	I	
256K x 18	GS841Z18AT-150I	NBT Pipeline/Flow Through	TQFP	150/10	I	
256K x 18	GS841Z18AT-100I	NBT Pipeline/Flow Through	TQFP	100/12	I	
128K x 36	GS841Z36AT-180I	NBT Pipeline/Flow Through	TQFP	180/8	I	
128K x 36	GS841Z36AT-166I	NBT Pipeline/Flow Through	TQFP	166/8.5	I	
128K x 36	GS841Z36AT-150I	NBT Pipeline/Flow Through	TQFP	150/10	I	
128K x 36	GS841Z36AT-100I	NBT Pipeline/Flow Through	TQFP	100/12	I	

Notes:

- Customers requiring delivery in Tape and Reel should add the character "T" to the end of the part number. Example: GS8Z36A-100IT.
- The speed column indicates the cycle frequency (MHz) of the device in Pipeline mode and the latency (ns) in Flow Through mode. Each device is Pipeline/Flow Through mode-selectable by the user.
- T_A = C = Commercial Temperature Range. T_A = I = Industrial Temperature Range.
- GSI offers other versions this type of device in many different configurations and with a variety of different features, only some of which are covered in this data sheet. See the GSI Technology web site (www.gsitechnology.com) for a complete listing of current offerings

4Mb Synchronous NBT Datasheet Revision History

DS/DateRev. Code: Old; New	Types of Changes Format or Content	Page /Revisions/Reason
841Z18A_r1		• Creation of new datasheet
841Z18A_r1; 841Z18A_r1_01	Content	<ul style="list-style-type: none"> • Changed description of E2 in pin description table (from active low to active high) • Removed pin locations from pin description table • Removed 200 MHz speed bin